

**NIKO-SEM**

# Dual N-Channel Enhancement Mode Field Effect Transistor

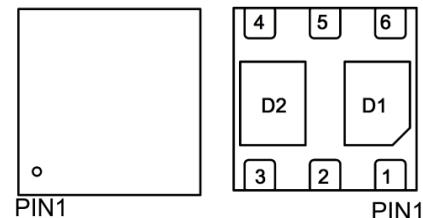
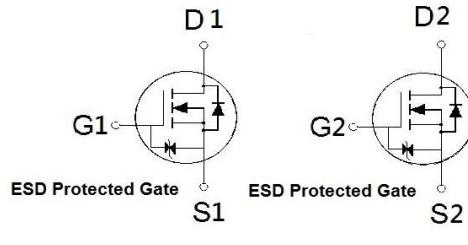
**PB5G8JW**  
**PDFN 2x2S**  
**Halogen-Free & Lead-Free**

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
20V	35mΩ	5A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low  $R_{DS(on)}$  to Minimize Conduction Losses.
- Ohmic Region Good  $R_{DS(on)}$  Ratio.
- Optimized Gate Charge to Minimize Switching Losses.
- Products Integrated ESD diode with ESD Protected.



100% RG Test , 100% UIL Test

1 : S1.    4 : S2.  
 2 : G1.    5 : G2.  
 3 : D2.    6 : D1.

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current  $T_A = 25^\circ\text{C}$	$I_D$	5	A
$T_A = 70^\circ\text{C}$		3.9	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	20	
Power Dissipation  $T_A = 25^\circ\text{C}$	$P_D$	1.4	W
$T_A = 70^\circ\text{C}$		0.9	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$		86	°C/W

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper.

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**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

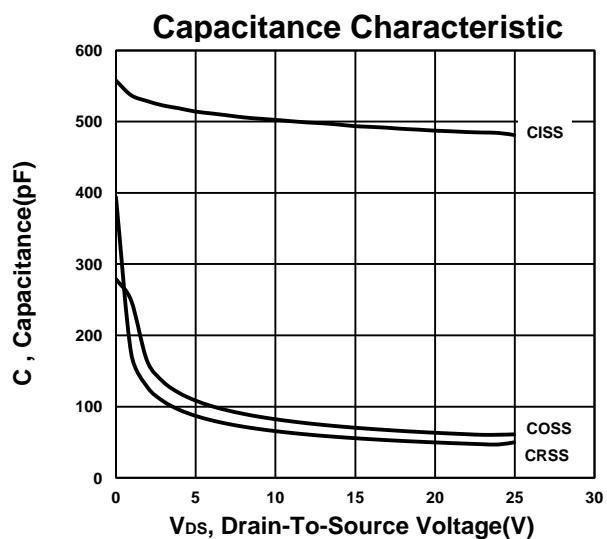
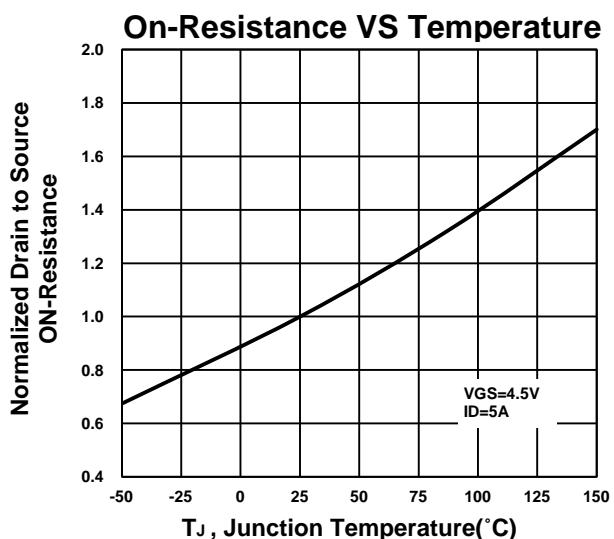
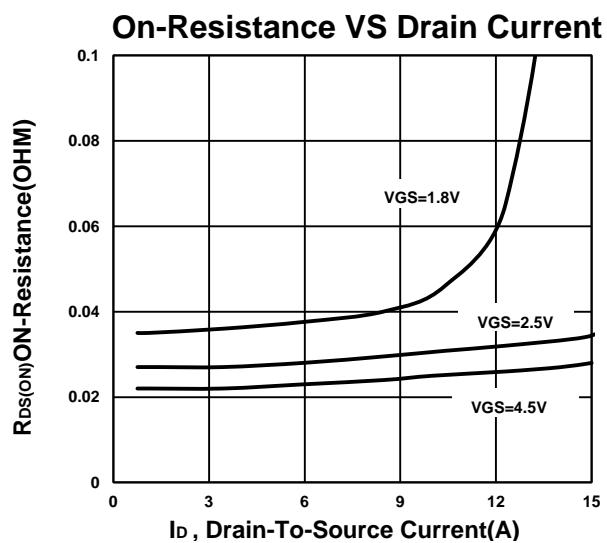
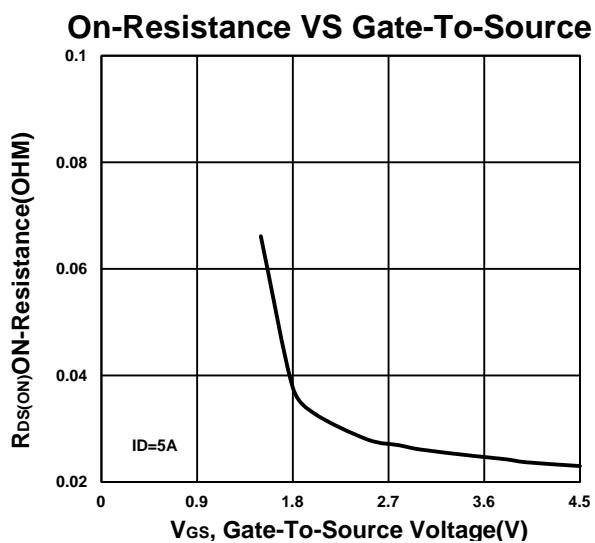
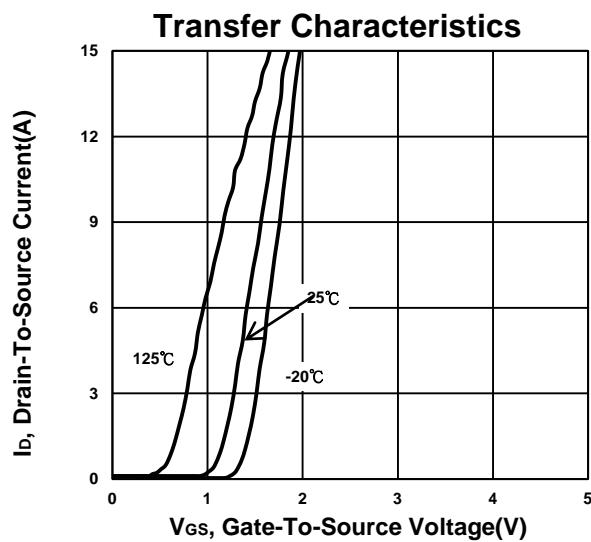
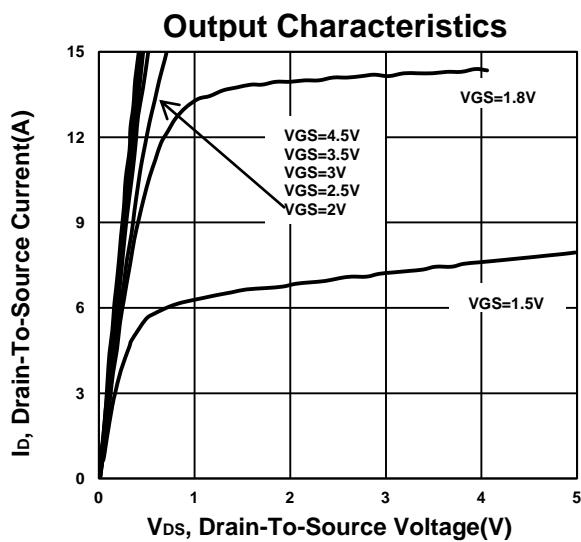
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	0.5	0.7	1	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 8\text{V}$			$\pm 10$	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}$			1	
		$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			10	$\mu\text{A}$
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 5\text{A}$		22	35	
		$V_{\text{GS}} = 2.5\text{V}, I_D = 4.5\text{A}$		27	38	$\text{m}\Omega$
		$V_{\text{GS}} = 1.8\text{V}, I_D = 2\text{A}$		35	55	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 5\text{V}, I_D = 5\text{A}$		30		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 10\text{V}, f = 1\text{MHz}$		506		
Output Capacitance	$C_{\text{oss}}$			82		$\text{pF}$
Reverse Transfer Capacitance	$C_{\text{rss}}$			66		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.8		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g(V_{\text{GS}}=4.5\text{V})$	$V_{\text{DS}} = 10\text{V}, I_D = 5\text{A}$		7		
	$Q_g(V_{\text{GS}}=2.5\text{V})$			4.3		$\text{nC}$
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$			0.6		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			2.3		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 10\text{V}$ $I_D \approx 5\text{A}, V_{\text{GEN}} = 4.5\text{V}, R_G = 6\Omega$		12		
Rise Time <sup>2</sup>	$t_r$			35		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$			24		$\text{nS}$
Fall Time <sup>2</sup>	$t_f$			16		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				1.4	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = 5\text{A}, V_{\text{GS}} = 0\text{V}$			1	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 5\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		8.8		$\text{nS}$
Reverse Recovery Charge	$Q_{\text{rr}}$			1.4		$\text{nC}$

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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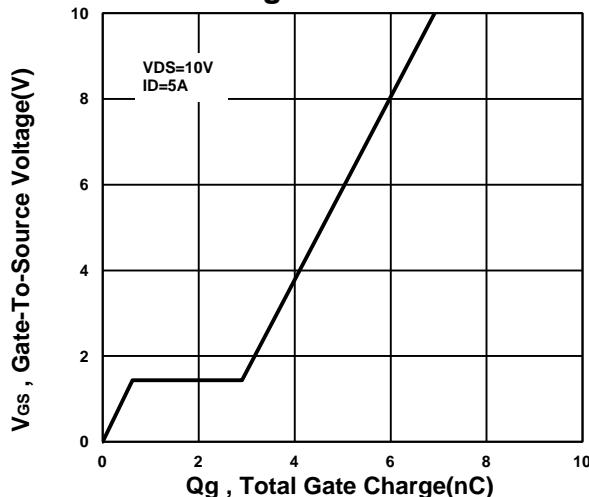


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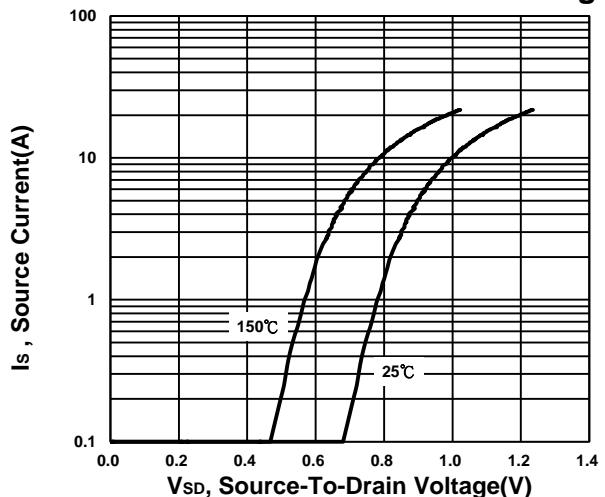
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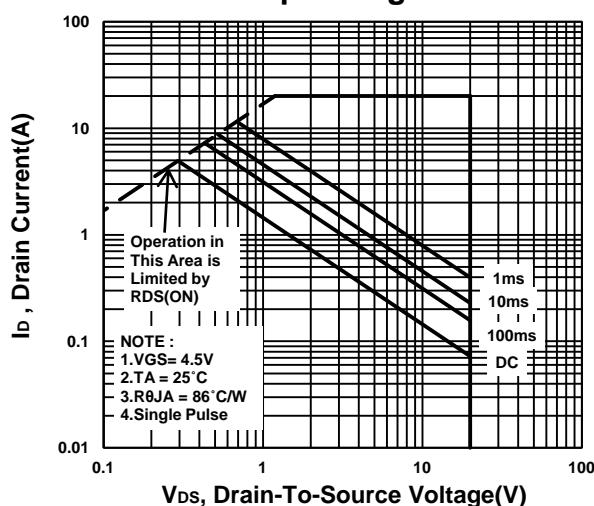
**Gate charge Characteristics**



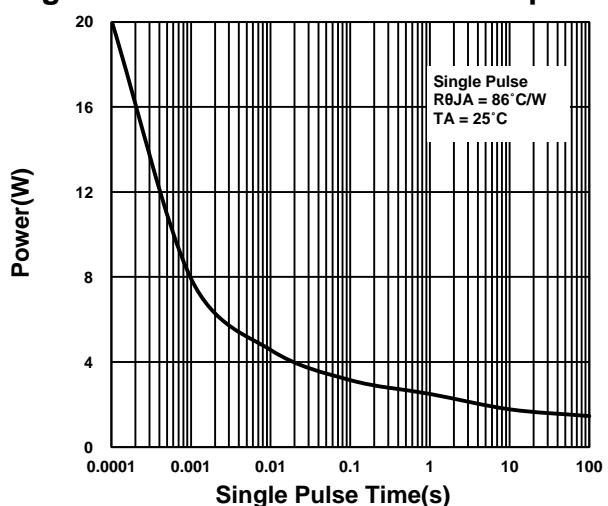
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

